

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/814,723 OFEK ET AL.	
		Examiner	Art Unit TAN TRINH	2618 Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,969,689	10-1999	Martek et al.	343/758
*	B	US-2004/0196834	10-2004	Ofek et al.	370/352
*	C	US-6,683,567	01-2004	De Champlain et al.	342/385
*	D	US-2003/0043071	03-2003	Lilly et al.	342/368
*	E	US-2002/0058503	05-2002	Gutowski, Stan J.	455/423
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.